Search	Notes

Application/Control No.	Applicant(s)/Patent und Reexamination	der
10/707,356	LEE ET AL.	
Examiner	Art Unit	
Paul D. Kim	3729	

	SEAR	CHED	
Class	Subclass	Date	Examiner
29	592.1 832	5/26/2006	PK
250	208.1 553		
257	40		
315	169.3		
	169.4 504	1	
345	205 207	ų.	
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INTERFERENCE SEARCHED			
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	ext Search achment	8/30/2006	PK

SEARCH (INCLUDING SEAF)
	DATE	EXMR
Consulted by Thuy Tran (315) No Search	2/14/2006	PK
Eddie Lee (257) No Search	3/21/2006	PK
Marie Yamnitzky (428) No Search	2/13/2006	PK
Review the US Applicantion 10/707,355 (Pending)	5/26/2006	PK
Text Search EAST/NPL (IEEE)	5/26/2006	PK
Updated Text Search EAST/PGPub	8/30/2006	PK